



Assignment No. 1

CMOS 2:1 Multiplexor using SPICE

Rev: 01	Dt: 03/08/2005	
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1. Introduction

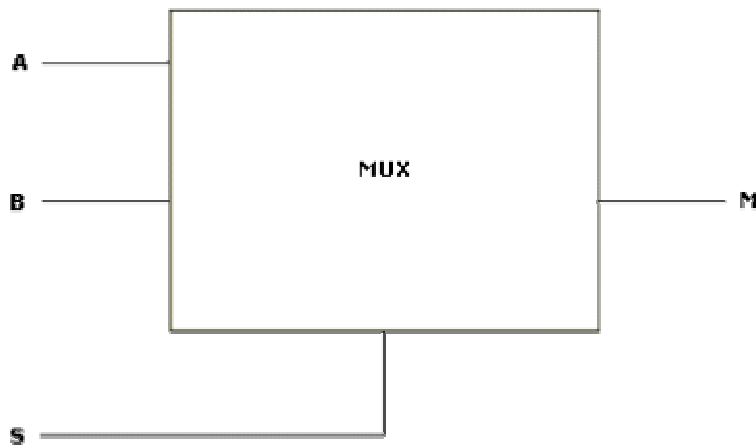
1. CMOS Multiplexor

The multiplexor is a very popular and most widely used combinational circuit. It has multiple inputs and one output. The input can be selected by a set of select lines. Multiplexors are key components in CMOS memory elements and data manipulation structures.

2. Block Diagram

CMOS 2:1 Multiplexor

The following figure shows the block diagram of full custom cell (CMOS) of 2 to 1 multiplexor. A 2 to 1 multiplexor has two inputs (A and B) and one select line(S). The circuit should select input A when $S=0$ and input B when $S=1$.





3 Functional Circuit

The truth table of 2:1 Multiplexor is shown below

A	B	S	M
0	0	0	0
0	0	1	0
0	1	0	0
0	1	1	1
1	0	0	1
1	0	1	0
1	1	0	1
1	1	1	1

Karnaugh Map of 2:1 Multiplexor

		AB			
		00	01	11	10
S	0	0	0	1	1
	1	0	1	1	0

$$\bar{M} = \bar{S} \cdot \bar{A} + S \cdot \bar{B}$$

The decomposition of this expression and generation of the CMOS transistor circuit diagram is approached in following way:

- i) For the n-side, take the un-inverted expression ($\bar{S} \cdot \bar{A} + S \cdot \bar{B}$); AND (.) operations are converted in series connection of NMOS while OR (+) operations are converted in parallel connection of NMOS.

For NMOS

$$M = \overline{(\bar{S} \cdot \bar{A} + S \cdot \bar{B})}$$

- ii) For the p-side invert the expression used for the n-expansion, yielding $(\bar{S} + \bar{A}) \cdot (S + \bar{B})$. (replacing AND with OR and vice-versa). OR (+)



operations are converted in parallel connection of PMOS while AND (.) operations are converted in series connection of PMOS.

For PMOS

$$M = \overline{((\overline{S} + \overline{A}) \cdot (S + \overline{B}))}$$

- iii) The final step requires connecting one end of the p-structure to '1' (VDD) and other to the output M. One side of the n-structure is connected to '0' (VSS) and other to the output in common with the PMOS.

This final diagram of multiplexor is yield below.

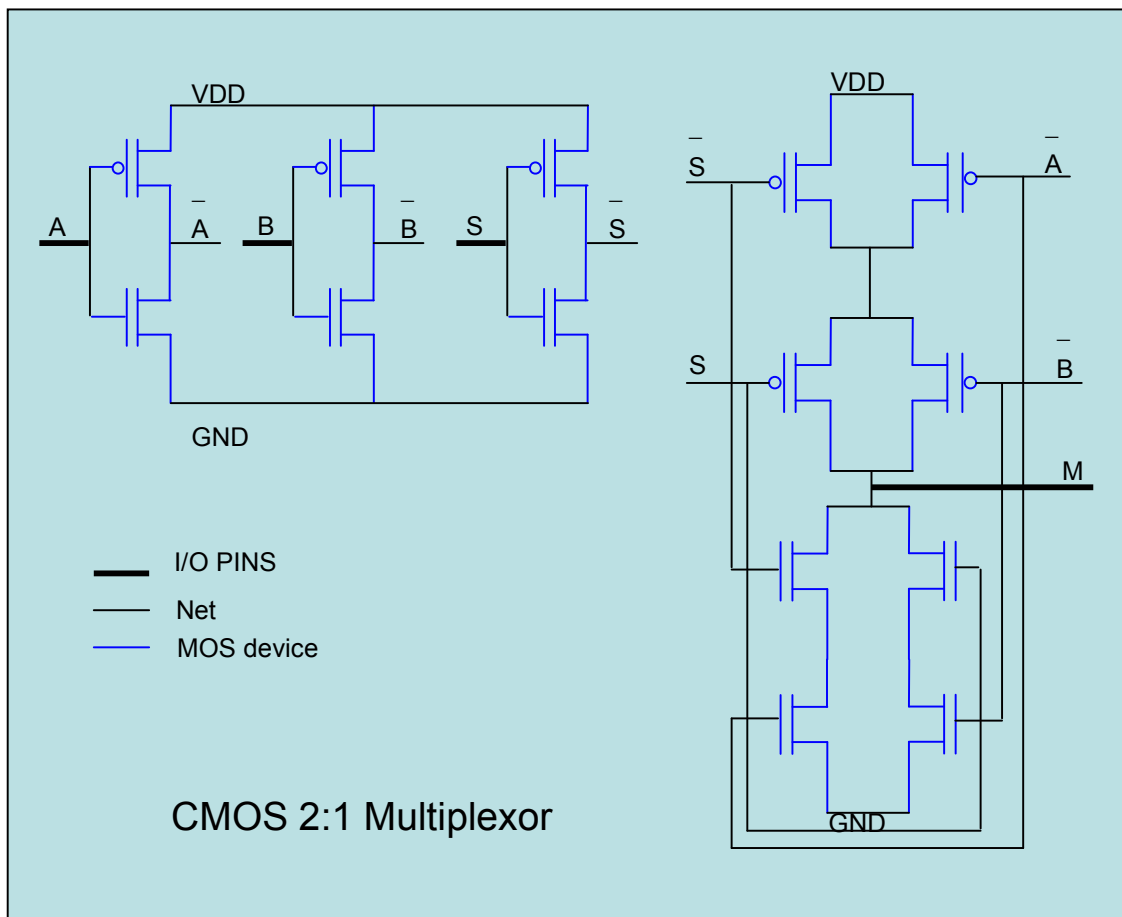


Fig. 1.3 CMOS 2:1 Multiplexor



4. Schematic

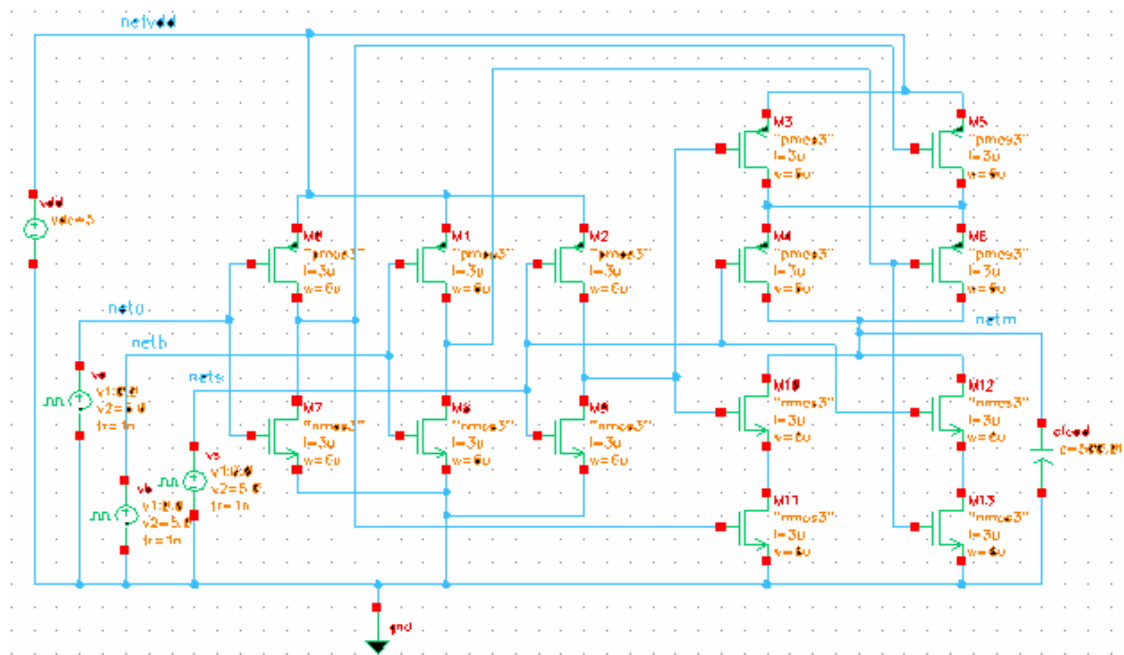


Fig. 1.4 Internal Schematic of Multiplexor cell



5. Circuit Simulation

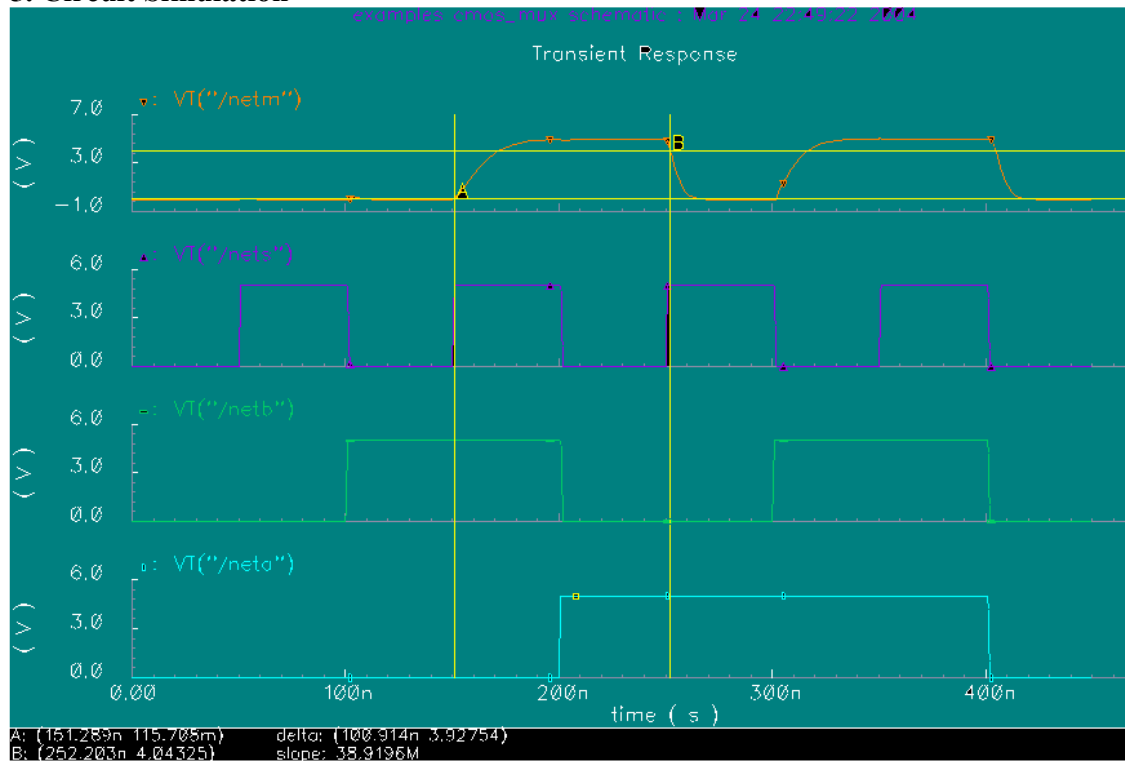


Fig.1.5 Transient Response of Input A, B, S and Output M.

Input A (neta - sky blue color)

Delay Time= 200ns

Pulse Width= 200ns

Period= 400ns

Input B (netb - green color)

Delay Time= 100ns

Pulse Width= 100ns

Period= 200ns

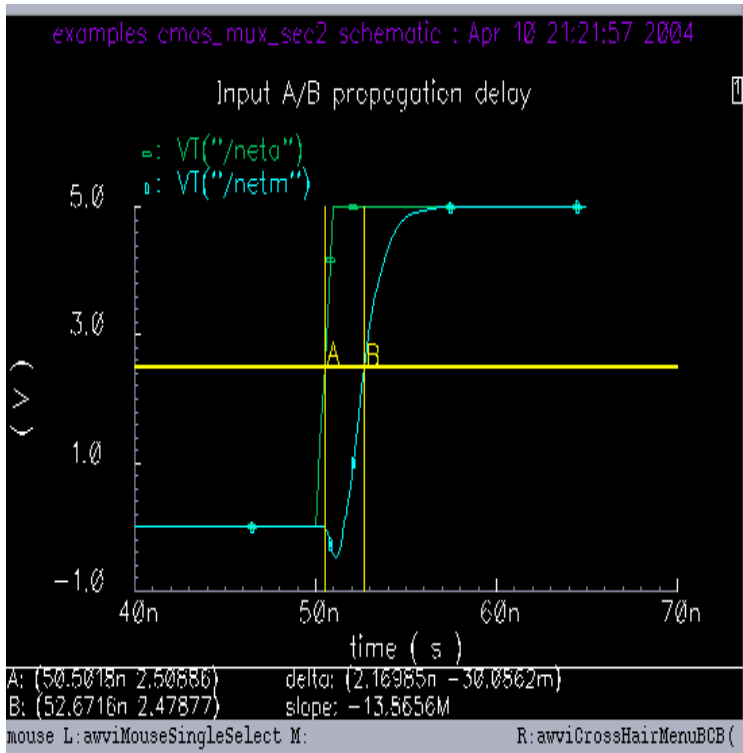
Input S (nets - blue color)

Delay Time= 50ns

Pulse Width= 50ns

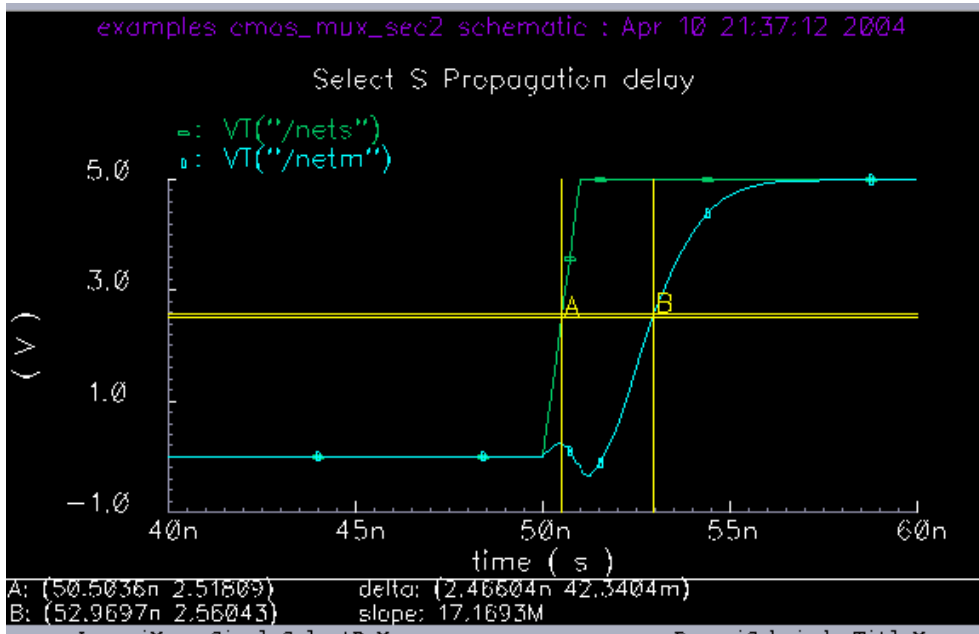
Period= 100ns

Result Output (netm - yellow color)



Propagation delay a, b to m

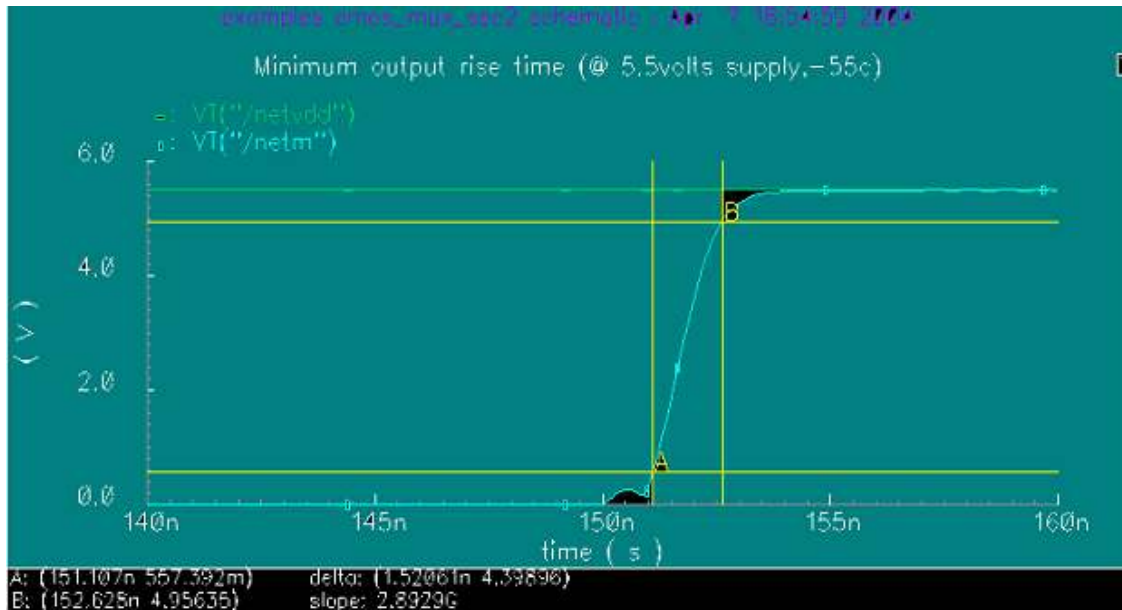
Propagation Delay



Propagation delay s to m

2. Parameters of the cell

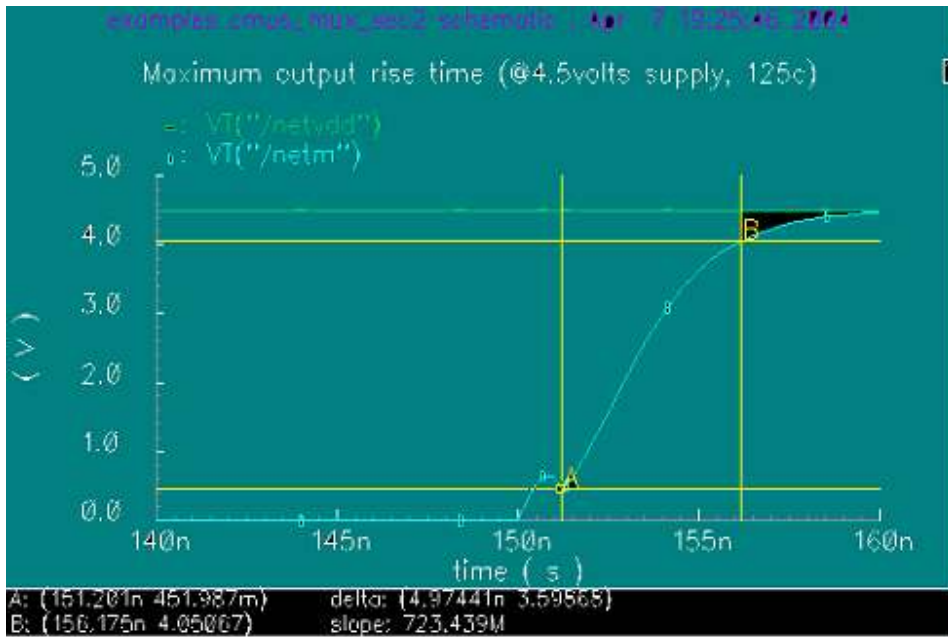
Figure Number	Vdd	Temp (°C)	Parameter	Description
2.1	5.5v	-55	$t_{rmin} = 1.52ns$	Minimum output rise time
2.2	5.0v	25	$t_{rtyp} = 2.75ns$	Typical output rise time
2.3	4.5v	125	$t_{rmax} = 4.97ns$	Maximum output rise time
2.4	5.5v	-55	$t_{fmin} = 0.53ns$	Minimum output fall time
2.5	5.0v	25	$t_{ftyp} = 0.72ns$	Typical output fall time
2.6	4.5v	125	$t_{fmax} = 1.14ns$	Maximum output fall time
2.7	5.0	25	$t_{rdel} = 7.0ns$	Additional output rise time delay per unit load of 0.1pf
2.8	5.0	25	$t_{fdel} = 2.35ns$	Additional output fall time delay per unit load of 0.1pf
2.9	5.5	-55	$I_{swmax} = 944uA$	Maximum switching current taken from the supply. (load=0.1pf)



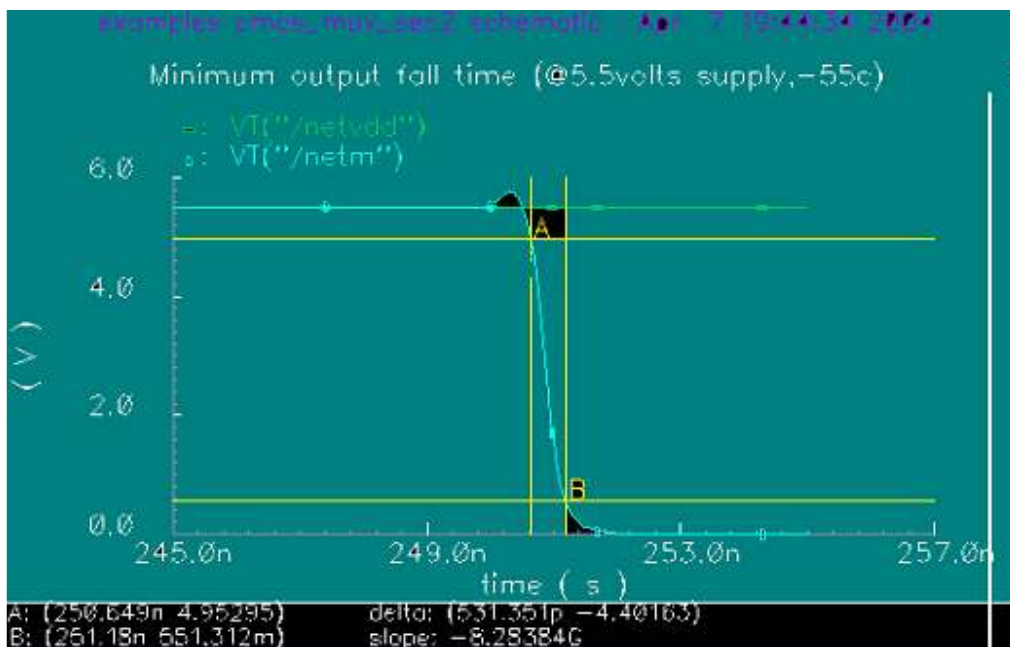
2.1 Minimum output rise time (1.52ns)



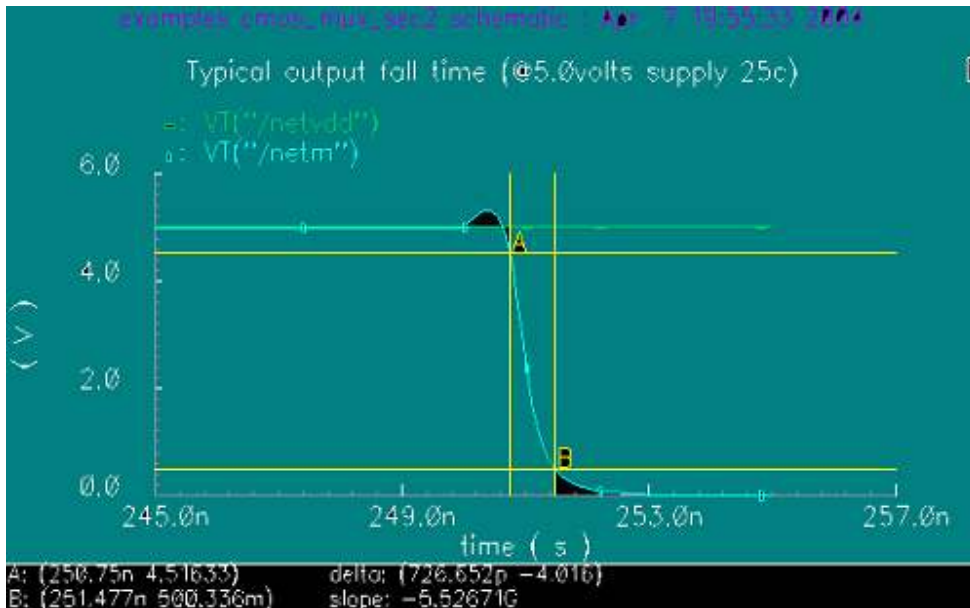
2.2 Typical output rise time (2.75ns)



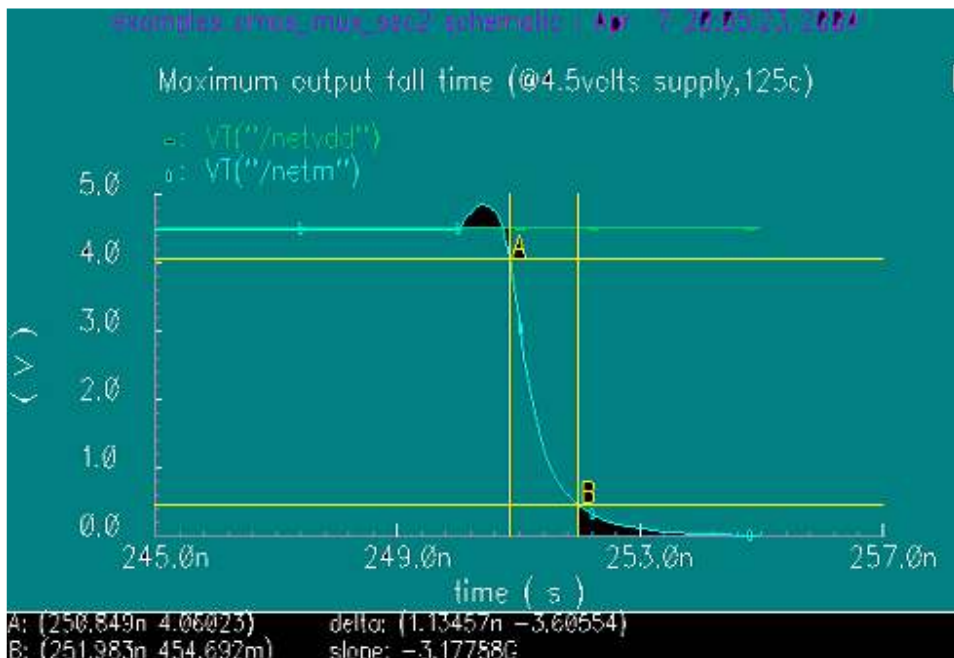
2.3 Maximum output rise time (4.97ns)



2.4 Minimum output fall time (0.53ns)



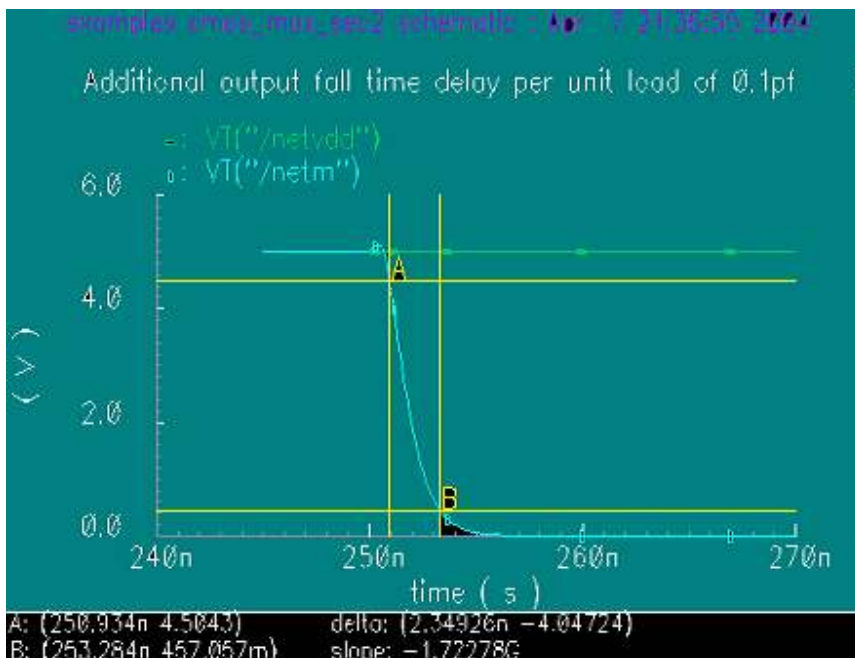
2.5 Typical output fall time (0.72ns)



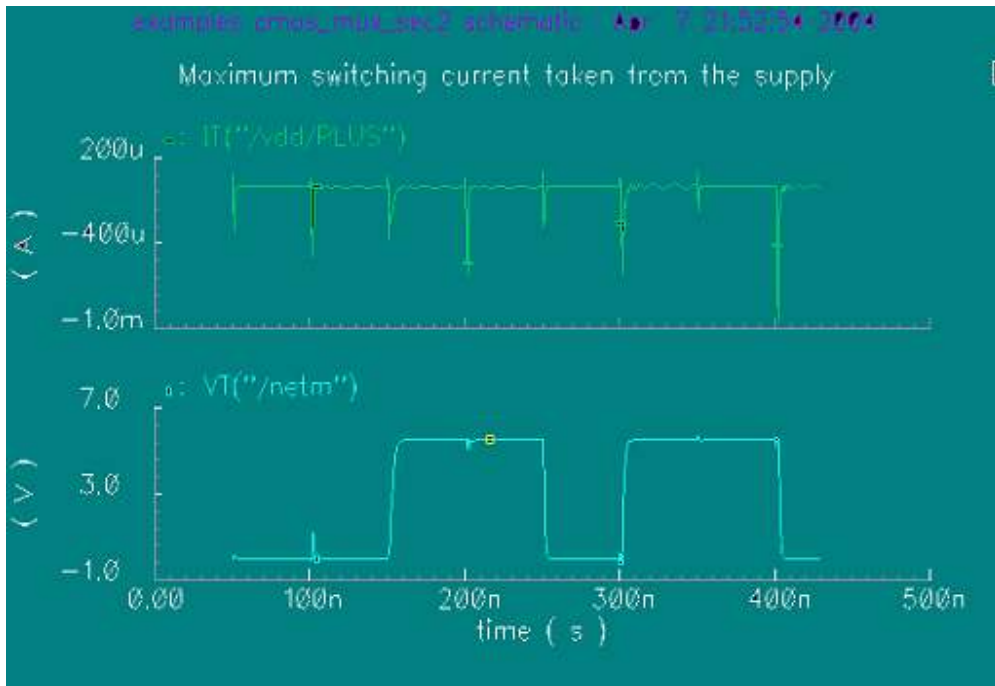
2.6 Maximum output fall time (1.14ns)



2.7 Additional output rise time delay per unit load of 0.1pf (7.0ns)



2.8 Additional output fall time delay per unit load of 0.1pf (2.35ns)



2.9 Maximum switching current taken from the supply (944uA)

3. DC transfer curve

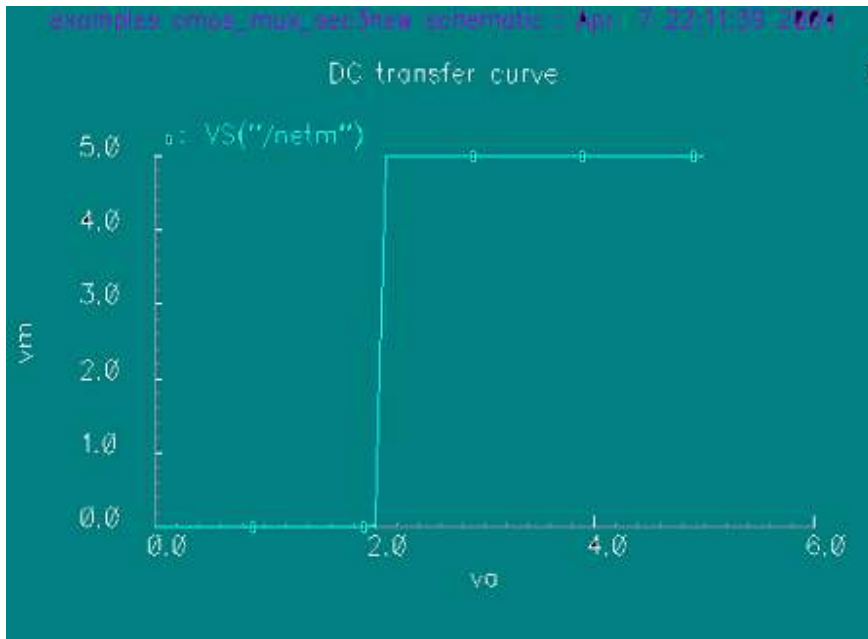
Input B = 0v

S = 0v

Vcc = 5V, Temperature = 27°C,

Load = 0.1pf.

Input A is swept from 0 to 5V while measuring output M.



DC transfer curve of va (input) VS vm (output)

FEATURES

- 5V tolerant inputs/outputs, for interfacing with 5V logic.
- Specified from -55 to 125 °C
- Output drive capability 50 ohms transmission lines at 85 °C
- CMOS power levels
- Resistor outputs (-15mA IOH, 12mA IOL)

Quick Reference Data

GND = 0V; $t_r = 2.75\text{ns}$ $t_f = 0.72\text{ns}$; $T_{amb} = 25\text{ °C}$

SYMBOL	PARAMETER	CONDITIONS	TYPICAL	UNIT
tPLH/tPHL	Propagation delay a, b to m	VDD= 5.0V unloaded	2.16	ns
	Propagation	VDD= 5.0V	2.46	ns



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	delay s to m	unloaded		
CI	Input capacitance		0.01pF	pF
CPD	Power dissipation capacitance per gate	VDD = 5.0V	15.9 pF	pF

$$C_{IN} = C_{gs} + C_{gd} = (2eA) / (3 t_{ox}) = 0.01pF$$

$$(e = 3.9 \times 8.854 \times 10^{-14}, t_{ox} = 200 \text{ \AA}, A = W \times L = 6\mu \times 3\mu)$$

$$C_{pd} = I / (V_{dd} \times F_i) - CL \text{ (eff)}$$

$$= 800 \text{ \AA} / (5 \times 1/100ns) - 0.1pf$$

$$= 15.9 \text{ pF}$$

Recommended Operating Conditions

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
VDD	Supply Voltage	for normal operation	4.5	5.5	V
Vi	Input voltage		0	5.5	V
Vo	Output voltage	High or Low state	0	VDD	V
Tamb	Operating ambient temperature	In free air	-55	+125	°C
tr, tf	Input rise and fall times	VDD = 5.0V	0.72	2.75	ns

$$P_{ave} = CL V_{dd}^2 f \text{ where } f = 1/T$$

$$= 0.1pF * 5.0 * 5.0 * (1/100ns)$$

$$= 25 \text{ \AA}$$

$$P_{sc} = (\beta/12)(V_{dd} - 2V_t)^3 (trf/tp)$$

$$(\beta = 30 \text{ \AA}/V^2, V_{dd} = 5.0V, V_t = , trf = 1ns, tp = 100ns)$$

$$= (2.5) (5-2) (0.03)$$

$$= 0.225 \text{ \AA}$$

where t_p is the period of the input waveform and trf is the total risetime (or falltime)
 $tr = tf = trf$

$$P_s = \sum 1-n \text{ Leakage current} * \text{ supply voltage (number of devices)}$$

$$= \sum 1-14 (0.2 \text{ nA} * 5.0V)$$

$$= \sum 1-14 (1nw)$$

$$= 14 \text{ nw}$$

$$P_{total} = P_d + P_{sc} + P_s$$



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$$= 25\mu w + 0.225\mu w + 14\text{n}w$$

$$= 25.24\mu w$$

where P_d is the dynamic average power (previous chart), P_{sc} is the short circuit power, and P_s is the static power due to ratio circuit current, junction leakage, and subthreshold I_{off} leakage current

DC CHARACTERISTICS

At recommended operating conditions; voltages are referenced to GND (ground = 0V).

SYMBOL	PARAMETER	Test Conditions		MIN.	TYP.	MAX.	UNIT
		Other	VCC (V)				
Tamb = -55 to 125 °C; note 1							
V _{IH}	HIGH-level input voltage	Guaranteed Logic HIGH Level		2.8	-	-	V
V _{IL}	LOW-level input voltage	Guaranteed Logic LOW Level		-	-	2.0	V
I _{IH}	Input HIGH Current(4)	V _I = 2.7V	V _{CC} = Max.	-	-		μA
I _{IL}	Input LOW Current(4)	V _I = 0.5V	V _{CC} = Max.	-	-		μA
I _I	Input HIGH Current(4)	V _I = V _{CC} (Max.)	V _{CC} = Max.	-	-		μA
V _{OH}	HIGH-level output voltage	V _I = V _{IH} or V _{IL} I _O = -100 μA I _O = -12 mA I _O = -18 mA I _O = -24 mA	V _{CC} = Min	4.8			V
V _{OL}	LOW- level output voltage	V _I = V _{IH} or V _{IL} I _O = 100 μA I _O = 12 mA I _O = 24 mA	V _{CC} = Min	0.1			V
I _{LI}	Input leakage current	V _I = 5.5 V or GND					μA
I _{OZ}	3-state output OFF-state current	V _I = V _{IH} or V _{IL} ; V _O = 5.5 V or GND					μA
I _{OFF}	Power-off leakage supply	V _I or V _O = 5.5 V					μA
I _{CC}	quiescent supply current	V _I = V _{CC} or GND; I _O = 0	V _{CC} = Max.	-			μA
ΔI _{CC}	Additional quiescent supply	V _I = V _{CC} - 0.6 V; I _O = 0	V _{CC} = Max.				μA



	current per pin						

Notes

1. All typical values are measured $T_{amb} = 25\text{ }^{\circ}\text{C}$

OUTPUT DRIVE CHARACTERISTICS

Symbol	Parameter	Test Conditions(1)	Min.	Typ.(2)	Max.	Unit
I _{ODL}	Output LOW Current	V _{CC} = 5V, V _{IN} = V _{IH} or V _{IL} , V _{OUT} = 1.5V(3)			-	
I _{ODH}	Output HIGH Current	V _{CC} = 5V, V _{IN} = V _{IH} or V _{IL} , V _{OUT} = 1.5V(3)			-	

NOTES:

1. For conditions shown as Min. or Max., use appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical values are at V_{CC} = 5.0V, +25°C ambient.
3. Not more than one output should be tested at one time. Duration of the test should not exceed one second.
4. The test limit for this parameter is $\pm 5\text{mA}$ at T_A = -55°C.

POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions(1)	Min.	Typ.(2)	Max.	Unit
ΔI _{CC}	Quiescent Power Supply Current TTL Inputs HIGH	V _{CC} = Max. V _{IN} = 3.4V(3)	-			mA
I _{CCD}	Dynamic Power Supply Current(4)	V _{CC} = Max. Outputs Open OE = GND One Input Toggling 50% Duty Cycle	V _{IN} = V _{CC} V _{IN} = GND			
I _C	Total Power Supply Current(6)	V _{CC} = Max. Outputs Open f _o = 10MHz	V _{IN} = V _{CC} V _{IN} = GND			
		50% Duty	V _{IN} = 3.4V	-		



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		Cycle OE = GND VIN = GND One Bit Toggling				
		VCC = Max. Outputs Open fo = 2.5MHz 50% Duty Cycle OE = GND Four Bits Toggling	VIN = VCC VIN = GND VIN = 3.4V VIN = GND			

NOTES:

1. For conditions shown as Min. or Max., use appropriate value specified under Electrical Characteristics for the applicable device type.
 2. Typical values are at VCC = 5.0V, +25°C ambient.
 3. Per TTL driven input (VIN = 3.4V). All other inputs at VCC or GND.
 4. This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
 5. Values for these conditions are examples of \square ICC formula. These limits are guaranteed but not tested.
 6. IC = IQUIESCENT + IINPUTS + IDYNAMIC
- $IC = ICC + \square ICC_{DHNT} + ICCD(f_{NO})$
 ICC = Quiescent Current
 $\square ICC$ = Power Supply Current for a TTL High Input (VIN = 3.4V)
 DH = Duty Cycle for TTL Inputs High
 NT = Number of TTL Inputs at DH
 ICCD = Dynamic Current caused by an Input Transition Pair (HLH or LHL)
 fo = Output Frequency
 NO = Number of Outputs at fo
 All currents are in milliamps and all frequencies are in megahertz.

CAPACITANCE (Ta = +25 °C, F = 1.0 MHz)

Symbol	Parameter(1)	Conditions	Typ.	Max.	Unit
CIN	Input Capacitance	VIN = 0V	6	10	pF
COUT	Output Capacitance	VOUT = 0V	8	12	pF

NOTE:

1. This parameter is measured at characterization but not tested.



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Applications
Digital Multiplexing
Signal Gating